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CONFIRMATION NO. 2565

Bib Data Sheet

SERIAL NUMBER 10/633,414	FILING DATE 08/04/2003 RULE	CLASS 073	GROUP ART UNIT 2856	ATTORNEY DOCKET NO. 2019-0207P	
APPLICANTS Chih-Kun Chen, Pa Te City, TAIWAN; Yao-Hsiung Kung, Lu Chu Hsiang, TAIWAN; Tun Yuan Lo, Chung Li City, TAIWAN; ** CONTINUING DATA ***** <i>None</i> ** FOREIGN APPLICATIONS ***** <i>None</i> IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 10/30/2003					
Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 (a-d) conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after Allowance Verified and Acknowledged <i>[Signature]</i> Examiner's Signature Initials		STATE OR COUNTRY TAIWAN	SHEETS DRAWING 5	TOTAL CLAIMS 12	INDEPENDENT CLAIMS 2
ADDRESS 02292 BIRCH STEWART KOLASCH & BIRCH PO BOX 747 FALLS CHURCH, VA 22040-0747					
TITLE Method and apparatus for detecting wafer flaw					
FILING FEE RECEIVED 750	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		